# Application/Control No. 10/045,441 Examiner Timothy H. Meeks Applicant(s)/Patent Under Reexamination FABIAN, HEINZ Art Unit Page 1 of 1

# Notice of References Cited

### **U.S. PATENT DOCUMENTS**

	U.S. FATER DOCUMENTS					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
	Α	US-6,003,342	12-1999 <sup>.</sup>	Ishida et al.	65/484	
	В	US-				
	С	US-				
	D	US-				
	Е	US-				
	F	US-				
	G	US-			·	
	Н	US-				
	-	US-				
	J	US-				
	К	US-				
	L	US-		`		
	М	US-				

### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 56054242 A	05-1981	Japan	IMOTO et al.	C03B 37/00
	0	JP 58217448 A	12-1983	Japan	INAGAKI et al.	C03B 37/00
	Р	wo-9803441-a1	01-1998	wo		
	Q					
	R					
	s					
	T					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	V							
	w							
	x							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.